## جامعة المستقبل نحو جامعة مستدامة



Al-Mustaqbal University - College of engineering Department of computer engineering

Lecture Week 13

"Analog-to-Digital Converter (ADC)"

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2025

## **Learning Objectives**

## After this Lecture you will be able to:

- Determine the resolution and accuracy of a digitized analog signal.
- Explain how analog-to-digital converts operate
- Compare and contrast the characteristics several commonly used analog-to-digital converts operate

## **Analog-to-Digital Conversion (ADC)**

## Converting continuous signals to digital values requires 3 steps

1

Sample analog signal. Nyquist rate or above
Need a minimum of 2x highest frequency
Higher rates ease signal reconstruction

2

Hold analog sample while conversion is in progress

3

Convert analog value to digital value (binary)

## Types of Analog-to-digital Converters

## Integrating

- High Accuracy
- Low Speed
- Low Cost
- Not commonly used in DAQ

## Tracking (Counter Type)

- High Speed in tracking mode
- Slow
   Conversion
   times (Some
   Sub-types)
- Noise Sensitive

## Successive Approximation

- Conversion time independent of input value
- Most commonly used in DAQ applications

# Digital Systems

## Types of Analog-to-digital Converters

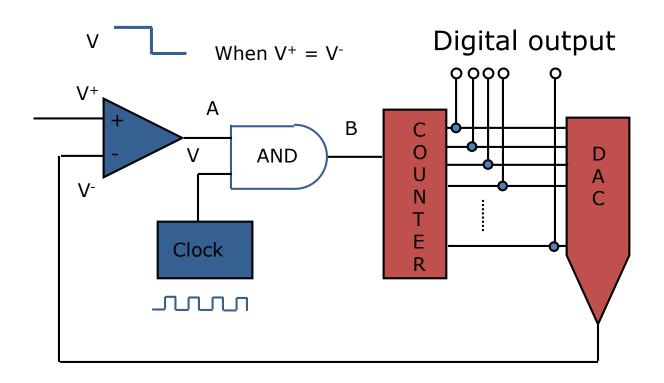
## "Flash" or Parallel

- Multi-Comparators
- Highest Speed
- High Cost

## Delta/Sigma

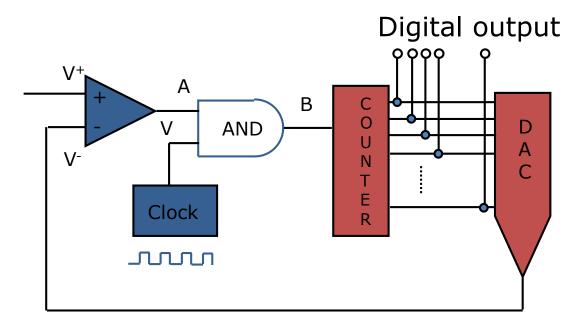
- One bit Conversion
- High Resolution
- Ratio of 1to-0 represent input
- Uses digital filtering

#### **Counter-Type Analog-to-Digital Converter Operation**



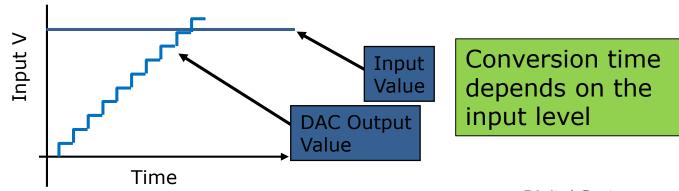
- 1.) Input a constant value. Requires a sample and hold circuit. (Not Shown)
- 2.) AND gate passes clock signal when point A logic high
- 3.) Counter incremented by signal B
- 4.) DAC output increases as counter output increases

## COUNTER-TYPE ANALOG-TO-DIGITAL CONVERTER OPERATION



Tracking A/D converters use up/down counters to minimize conversion times

## 5.) Counter stops when DAC V exceeds input V



### **Successive Approximation ADC**

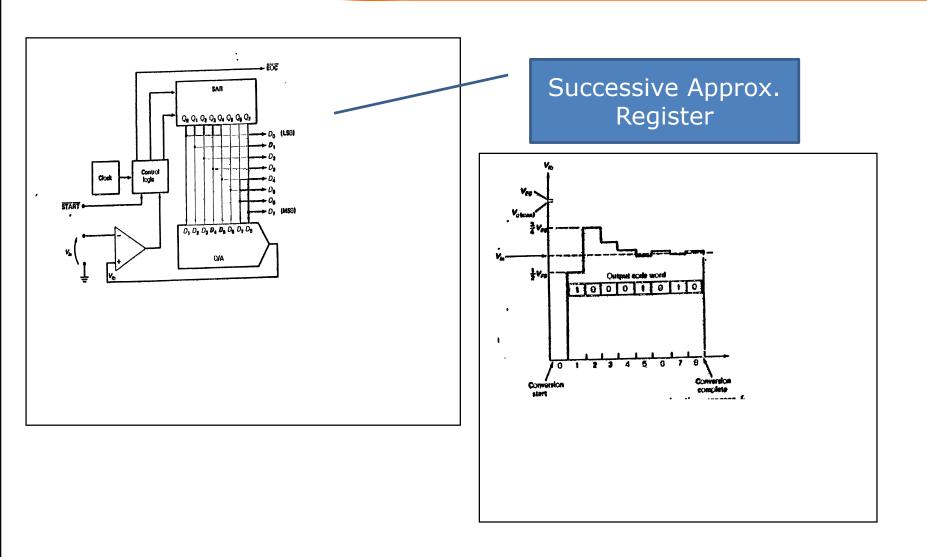
Counter A/D converters conversion time proportional to the input level. Improve conversion speed using a binary search technique.

#### **Procedure**

- 1. Set MSB to 1
- 2. Test input, V<sub>in</sub>, against DAC output, V<sub>DAC</sub>
- 3. If  $V_{DAC} > V_{in}$ , reset bit to 0, else bit = 1 ( $V_{DAC} < V_{in}$ )
- 4. Move to next bit and repeat steps 1 3

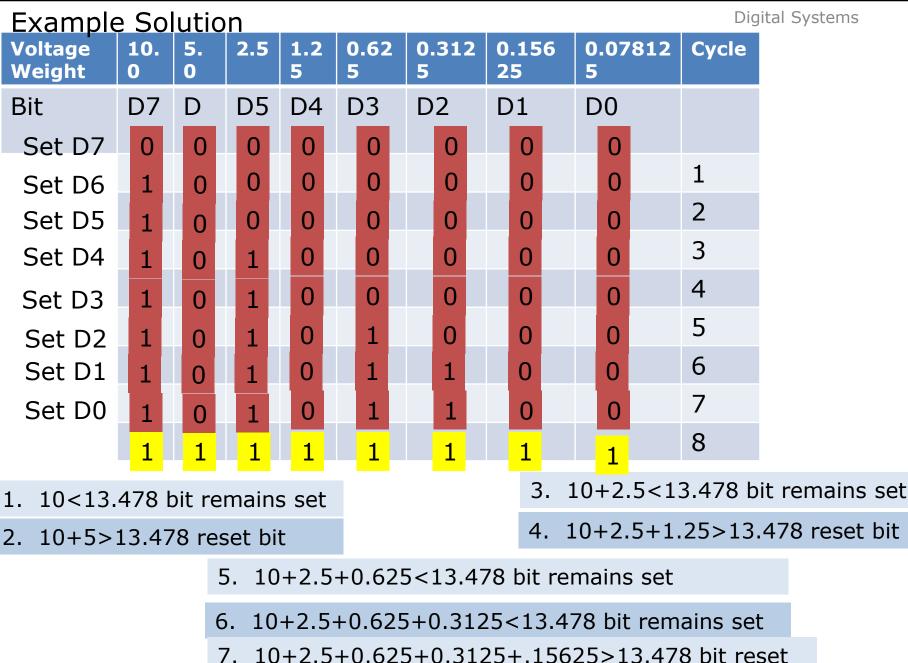
The input is converted to digital value in n steps, where n = the number of bits in digital representation

## **Successive Approximation ADCs**



## **Successive Approximation ADC**

**Example:** An 8-bit successive approximation ADC has an input voltage of 13.478 V. The ADC full scale input voltage is 20 V. Use the successive approximation algorithm given previously to determine the binary value. Assuming that each bit test takes a single clock cycle, determine the maximum conversion time for the ADC if it is clocked at 4.77 MHz.



11

10+2.5+0.625+0.3125+.15625+0.078125>13.478 bit reset

Example Solution (Continued)

### **Summary Results**

Final binary value:  $B=10101100_2$ 

Final voltage: 10+2.5+0.625+0.3125 = 13.4375 V

Quantization Error voltage:  $V_{OE}=13.478 \text{ V}-13.4375 \text{ V} =$ 

0.0405 V or 40.5 mV

#### Determine conversion time

Define  $T_c$  as clock period =  $1/f_c$  Where  $f_c$  = ADC Clock = 4.77 MHz

$$T_c = \frac{1}{f_c} = \frac{1}{4.77 \times 10^6 \, Hz} = 2.096 \times 10^{-7} \, S = 0.2096 \, \mu S$$

All conversions take 8 clock cycles so maximum conversion time is 8·T<sub>c</sub>

$$T_{con} = 8 \cdot T_c = 8 \cdot (0.2096 \ \mu S) = 1.667 \ \mu S$$
 Ans

### Example Solution (Continued)

What is the highest frequency that the system can convert without folding or aliasing. Assume that the sample and hold time is zero.

Define the maximum conversion rate frequency, f<sub>con(max)</sub>

$$f_{con(max)} = \frac{1}{T_{con}} = \frac{1}{1.677 \times 10^{-6} \text{S}} = 596,250 \text{ Hz}$$

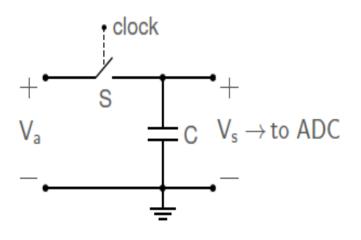
Signals must be sampled at least twice per period (Nyquist rate)

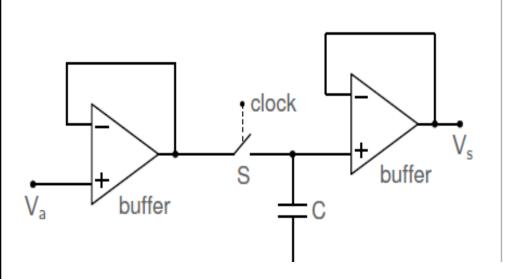
$$2 \cdot f_{in} = f_{con(max)}$$
 
$$f_{in} = \frac{f_{con(max)}}{2} = \frac{596,250 \text{ Hz}}{2} = 298,125 \text{ Hz}$$
 Ans

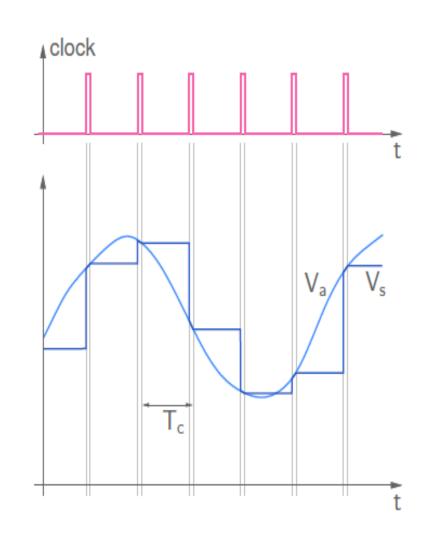
## **Open Questions**

- Is there another way to design low power ADCs?
- Is it recommended to reduce the analog part and put more effort in the digital part?
- How do I achieve a high SNR with low power ADCs?
- Is it better to have only one block with high frequency or many blocks with low frequency?
- How can asynchronous designs help me?
- How do I realize a low power ADC in sub-micron technologies?

## **ADC: sampling of input signal**



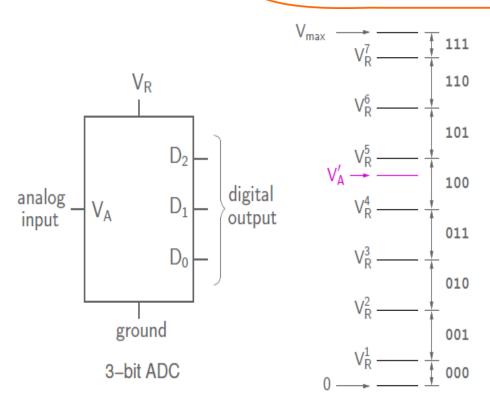




## **Application of ADC**

- ADC are used virtually everywhere where an analog signal has to be processed, stored, or transported in digital form.
- Some examples of ADC usage are digital volt meters, cell phone, thermocouples, and digital oscilloscope.
- Microcontrollers commonly use 8, 10, 12, or16 bit ADCs, our micro controller uses an 8 or 10 bit ADC

## Summary

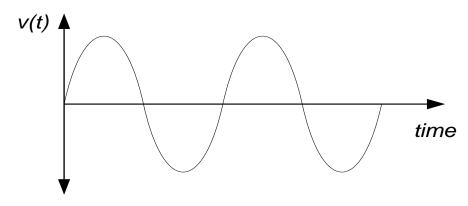


- \* If the input  $V_A$  is in the range  $V_R^k < V_A < V_R^{k+1}$ , the output is the binary number corresponding to the integer k. For example, for  $V_A = V_A'$ , the output is 100.
- \* We may think of each voltage interval (corresponding to 000, 001, etc.) as a "bin." In the above example, the input voltage  $V_A'$  falls in the 100 bin; therefore, the output of the ADC would be 100.
- \* Note that, for an N-bit ADC, there would be  $2^N$  bins.

## **Signal Reconstruction**

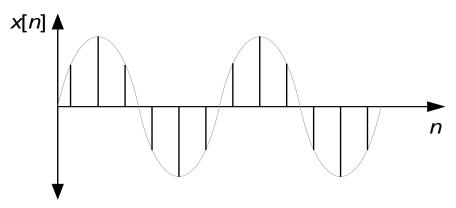
Continuous time (input signal):

$$V_{RMS\_ct} = \sqrt{\int_{-T/2}^{T/2} \frac{v(t)^2}{T} dt}$$



Discrete (reconstructed by ADC):

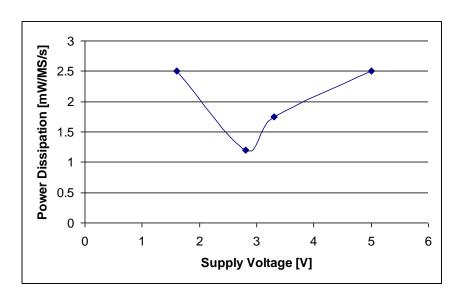
$$V_{RMS\_discrete} = \sqrt{\frac{\sum_{i=0}^{n} x[n]^2}{n}}$$



RMS: root mean square

## Voltage supply reduction [Tan00]

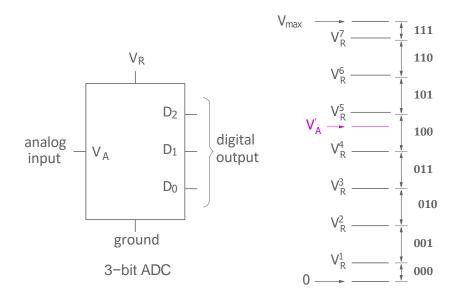
- For analog design, it is shown that a voltage supply reduction does not always lead to a power consumption reduction for several reasons:
  - Threshold of MOS transistors.
  - Loss of maximal amplitudes (SNR degradation).
  - Limits of conduction in analog switches.
  - Low speed of MOS transistors.
  - Limited stack of transistors.



Power consumption of 10-bit S-C 1.5 bit/stage pipelined ADCs in function of the voltage supply.

[Tan00] S. Tanner, Low-power architectures for single-chip digital image sensors, dissertation, University of Neuchatel, Switzerland, 2000.

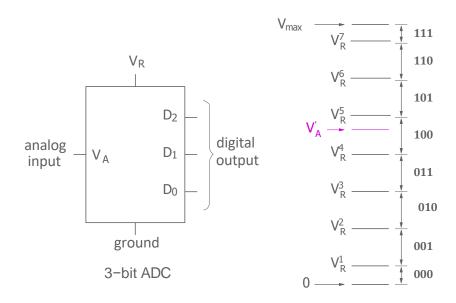
#### **ADC: introduction**



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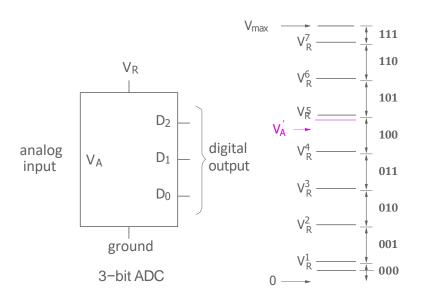
#### **ADC: introduction**

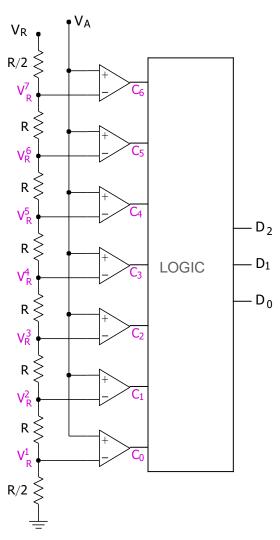


- \* The basic idea behind an ADC is simple:
  - Generate reference voltages  $V_{R'}^1$   $V_{R'}^2$  etc.
  - Compare the input  $V_A$  with each of  $V_R^i$  to figure out which bin it belongs to.
  - If  $V_A$  belongs to bin k (i.e.,  $V_R^k < V_A < V_R^{k+1}$ ), convert k to the binary format.
- \* A "parallel" ADC does exactly that  $\rightarrow$  next slide.



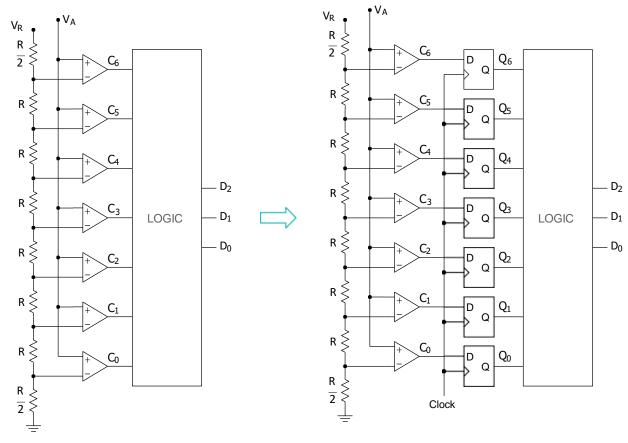
## 3-bit parallel (flash) ADC





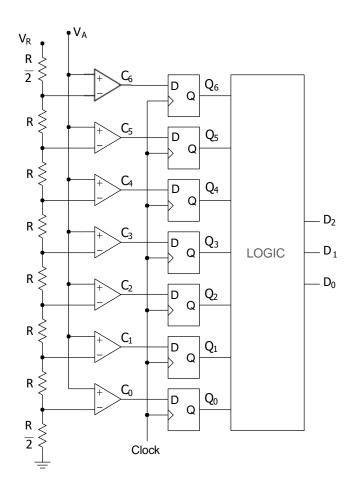


#### 3-bit parallel (flash) ADC



- \* Practical difficulty: As the input changes, the comparator outputs  $(C_0, C_1, \text{ etc.})$  may not settle to their new values at the same time.  $\rightarrow$  ADC output will depend on when we sample it.
- \* Add D flip-flops. Allow sufficient time (between the change in  $V_A$  and the active clock edge) so that the comparator outputs have already settled to their new values before they get latched in.

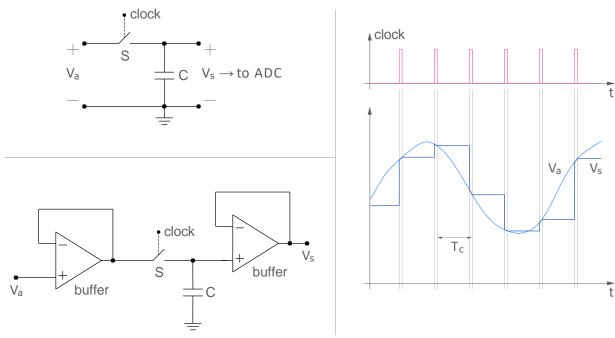
#### Parallel (flash) ADC



- \* In the parallel (flash) ADC, the conversion gets done "in parallel," since all comparators operate on the same input voltage.
- \* Conversion time is governed only by the comparator response time → fast conversion (hence the name "flash" converter).
- \* Flash ADCs to handle 500 million analog samples per second are commercially available.
- \*  $2^N$  comparators are required for N-bit ADC  $\rightarrow$  generally limited to 8 bits.



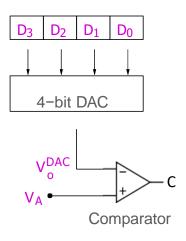
## **ADC: sampling of input signal**



- \* An ADC typically operates on a "sampled" input signal ( $V_s(t)$  in the figure) which is derived from the continuously varying input signal ( $V_a(t)$  in the figure) with a "sample-and-hold" (S/H) circuit.
- \* The S/H circuit samples the input signal  $V_a(t)$  at uniform intervals of duration  $T_c$ , the clock period.
- \* When the clock goes high, switch S (e.g., a FET or a CMOS pass gate) is closed, and the capacitor C gets charged to the signal voltage at that time. When the clock goes low, switch S is turned off, and C holds the voltage constant, as desired.
- \* Op-amp buffers can be used to minimise loading effects.

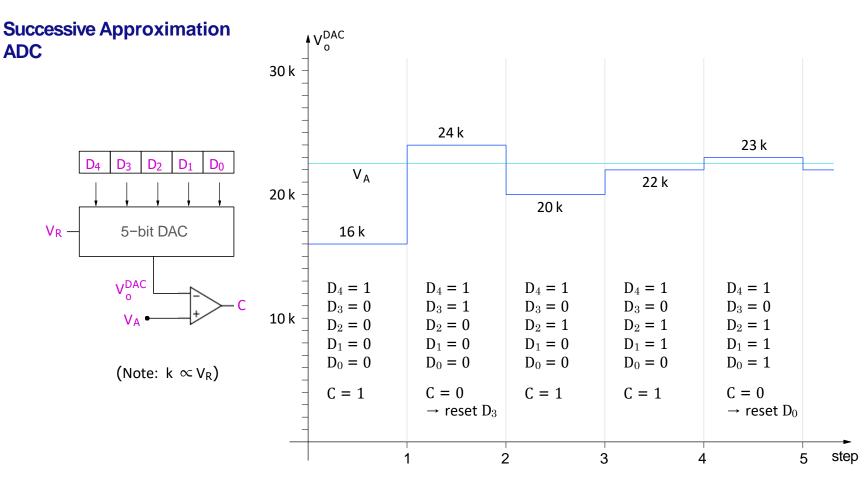


#### **Successive Approximation ADC**



- \* Suppose we have a 4-bit DAC. We can use it to perform A-to-D conversion by successively setting the four bits as follows.
  - Start with  $D_3D_2D_1D_0 = 0000$ , I = 3.
  - Set D[I] = 1 (keep other bits unchanged).
  - If  $V_0^{DAC} > V_A$  (i.e., C = 0), set D[I] = 0; else, keep D[I] = 1.
  - $I \rightarrow I 1$ ; go to step 1.
- \* At the end of four steps, the digital output is given by  $D_3D_2D_1D_0$ . Example  $\rightarrow$  next slide.

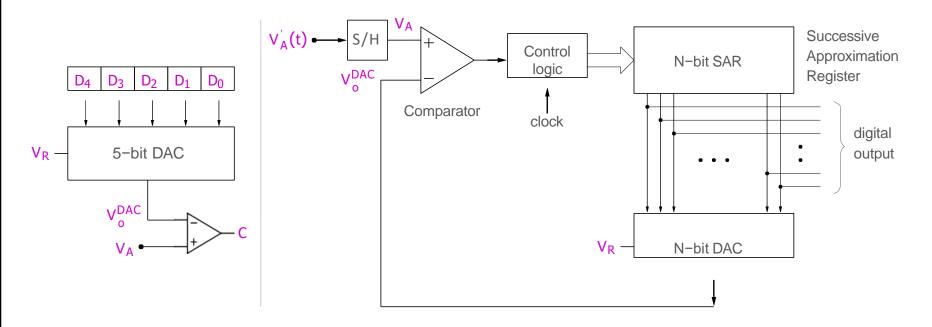




- $^{\ast}~$  At the end of the 5  $^{\text{th}}$  step, we know that the input voltage corresponds to 10110.
- \* For the digital representation to be accurate up to  $\pm \frac{1}{2}$  LSB,  $\Delta V$  corresponding to  $\frac{1}{2}$  LSB is added to  $V_A$  (see [Taub]).

Digi<del>t</del>al Systems

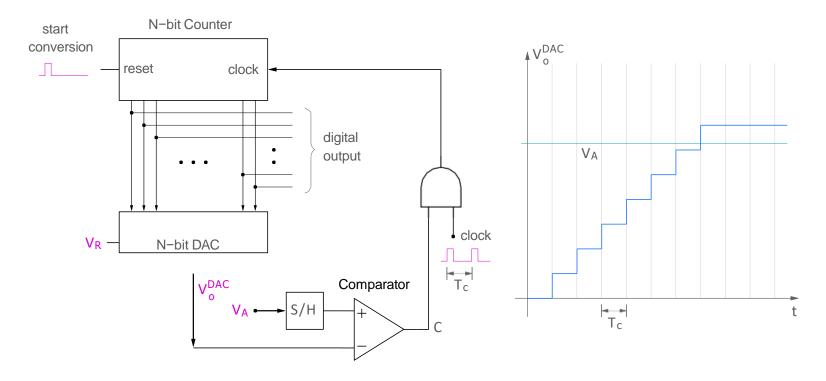
#### **Successive Approximation ADC**



- \* Each step (setting SAR bits, comparison of  $V_A$  and  $V_o^{DAC}$ ) is performed in one clock cycle  $\rightarrow$  conversion time is N cycles, irrespective of the input voltage value  $V_A$ .
- \* S. A. ADCs with built-in or external S/H (sample-and-hold) are available for 8- to 16-bit resolution and conversion times of a few  $\mu$ sec to tens of  $\mu$ sec.
- \* Useful for medium-speed applications such as speech transmission with PCM.



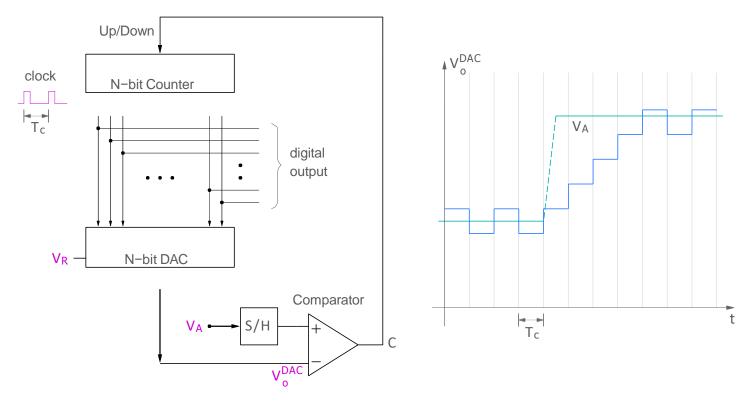
#### **Counting ADC (digital-ramp ADC)**



- \* The "start conversion" signal clears the counter; counting begins, and  $V_o^{DAC}$  increases with each clock cycle.
- \* When  $V_o^{DAC}$  exceeds  $V_A$ , C becomes 0, and counting stops.
- \* Simple scheme, but (a) conversion time depends on  $V_A$ , (b) slow (takes  $(2^N 1)$  clock cycles in the worst case)  $\rightarrow$  tracking ADC



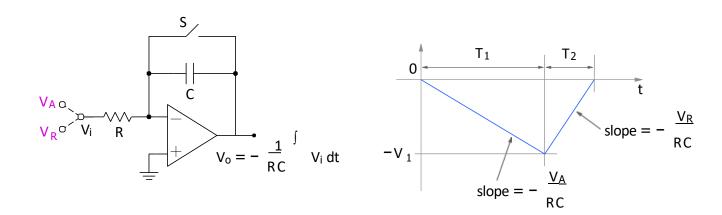
#### **Tracking ADC**



- \* The counter counts up if  $V_o^{DAC} < V_A$ ; else, it counts down.
- \* If  $V_A$  changes, the counter does not need to start from  $000\cdots 0$ , so the conversion time is less than that required by a counting ADC.
- \* used in low-cost, low-speed applications, e.g., measuring output from a temperature sensor or a strain gauge



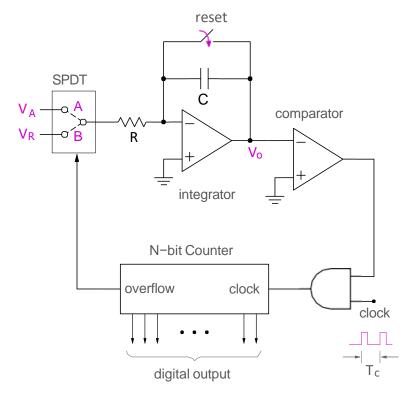
#### **Dual-slope ADC**

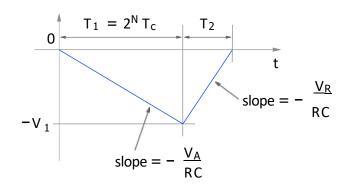


- \* t = 0: reset integrator output  $V_o$  to 0 V by closing S momentarily.
- \* Integrate  $V_A$  (voltage to be converted to digital format, assumed to be positive) for a fixed interval  $T_1$ .
- \* At  $t = T_1$ , integrator output reaches  $-V_1 = -V_A \frac{T_1}{RC}$ .
- \* Now apply a reference voltage  $V_R$  (assumed to be negative, with  $|V_R| > V_A$ ), and integrate until  $V_0$  reaches 0V.
- \* Since  $V_1 = V_A \frac{T_1}{RC} = |V_R| \frac{T_2}{RC}$ , we have  $T_2 = T_1 \frac{V_A}{|V_R|} \rightarrow T_2$  gives a measure of  $V_A$ .
- \* In the dual-slope ADC, a counter output which is proportional to  $T_2$  provides the desired digital output.



#### **Dual-slope ADC**





Start: counter reset to  $000 \cdots 0$ , SPDT in position A. Counter counts up to  $2^N$  at which point the overflow flag becomes 1, and SPDT switches to position B  $\rightarrow T_1 = 2^N T_c$ 

where  $T_c$  is the clock period. The counter starts counting again from  $000\cdots 0$ , and stops counting when  $V_o$  crosses 0 V. The counter output gives  $T_2$ in binary format.



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Department of Computer Engineering

## END LESSON 13: ANALOG-TO-DIGITAL CONVERTER (ADC)